Abstracts

New Time Domain Reflectometry Techniques Suitable for Testing Microwave and Millimeter Wave Circuits

Z.-Y. Shen. "New Time Domain Reflectometry Techniques Suitable for Testing Microwave and Millimeter Wave Circuits." 1990 MTT-S International Microwave Symposium Digest 90.3 (1990 Vol. III [MWSYM]): 1045-1048.

A superconducting circuit based time domain reflectometer with deconvolution has achieved a record 2.5 ps rise time at the DUT's interface. The corresponding spatial resolution is approaching 0.1mm for high dielectric media. Examples for applications are given. The "tail effect" caused by large discontinuities is eliminated by deconvolution. An innovative "partial reflection" calibration is suggested to improve the resolution for on-chip tests.

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